

Search Notes

Application/Control No.

10/706,757

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

CHOU ET AL.

Art Unit

1792

SEARCHED

Class	Subclass	Date	Examiner
216	41	12/18/2007	BT
216	44	12/18/2007	BT
216	49	12/18/2007	BT
216	53	12/18/2007	BT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using databases in EAST	12/18/2007	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner